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bcc Two Consecutive Conferences
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EVENTS



Attendees choose "best in show" products

Solid State Technology invited Semicon West attendees to vote on the best products they saw at the trade show, which took place from July 12 to 14 at San Francisco's Moscone Convention Center and from July 14 to 16 at the San Jose Convention Center.

There are three categories of awards, which were given BOTH in San Francisco -- The Wafer Processing Products -- and in San Jose -- The Final Manufacturing Products.

Ballots were available in the Attendees' Choice Awards Directory. Companies with a product listing in the directory appeared on the ballot; there was also a space included for write-in votes.

Wafer Processing Winners, Semicon West, San Francisco

Best solution to a problem: Lighthouse Worldwide Solutions' HH2016 particle counter. The handheld 2016 particle counter is claimed to be the first and only handheld counter with 0.2 micron sensitivity. Lighthouse Worldwide Solutions, San Jose, CA; ph 408/228-9200, info@golighthouse.com, www.golighthouse.com.



From left to right in the photo are: (front row) Rocco Pochy, engineer; Scott Salton, CTO; David Barach, SST publisher; Adam Giandomenico, president; and Kevin Fitzgerald, SST editor-in-chief; (back row) Martin Derks, country manager from Holland; Jim Shatting, VP channel sales; Peter Maguire, VP Asia Pacific; and Sean Birch, VP, US operations.



RESOURCE GUIDE



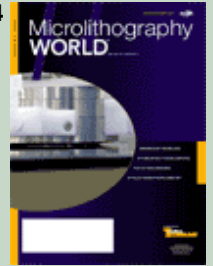
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Most innovative:

Applied Materials Inc. PDC Group's SEMVision G2 FIB analyzer. SEMVision G2 FIB defect-analysis system integrates SEM capability with automated focused ion-beam cross-sectioning and energy-dispersive x-ray analysis technology for high-speed, high-resolution defect review and analysis in one in-line production tool. Applied Materials Inc., Santa Clara, CA; ph 408/563-0647, e-mail betty_x_newboe@amat.com, www.appliedmaterials.com.



From left to right are: Sharon Wu, marketing communications manager for Applied Materials' Process Diagnostics and Control (PDC) Group; David Barach, *SS7* publisher; Jeremy Zelenko, global product manager for Applied Materials' Defect Review products; Yogev Barak, chief marketing officer for PDC Group; and Kevin Fitzgerald, *SS7* editor-in-chief.

Best cost-of-

ownership: KLA-Tencor Optical Metrology Div.'s SpectraCD 100 system. The SpectraCD 100 uses broadband spectroscopic ellipsometry with reflective optics across a continuous wavelength spectrum from 190-800nm to detect process issues that require extreme sensitivity, such as resist footers in gate structures. KLA-Tencor Corp., San Jose, CA; ph 408/875-4200, fax 408/875-4144, e-mail uma.subramaniam@kla-tencor.com, www.kla-tencor.com.



From left to right in the photo are: David Barach, *SS7* publisher; Mike Slessor, director of marketing, Optical CD Division, Patterning Solutions Group; Umar Whitney, senior field marketing manager, Patterning Solutions Group; Avi Cohen, group VP, Patterning Solutions Group; and Kevin Fitzgerald, *SS7* editor-in-chief.

Final Manufacturing Winners, Semicon West, San Jose

Best solution to a problem and Most innovative product: Multiprobe's Multiscan Atomic Force Probe (AFP). This Multiscan Atomic Force Probe quickly and repeatedly measures electrical performance characteristics of 90nm and 65nm transistors using multiple specialized atomic-force microscope heads, controlled by patent-pending Multiscan



IC MANUFACTURING BEST PRACTICES

True or False:

Leading IC manufacturers spend more on process control than other IC manufacturers.

CLICK TO ANSWER:

- TRUE
- FALSE

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Will chipmaking capacity be ready when demand escalates? (Comments? [Tell us.](#))

- Yes
- No
- Too early to tell

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software, to locate a failing transistor and contact closely spaced terminals. Multiprobe, Santa Barbara, CA; ph 805/560-0404, fax 805/560-0414, e-mail michele@multiprobe.com, www.multiprobe.com.



From left to right in the photo are: Kevin Fitzgerald, [SST](#) editor-in-chief; Andy Erickson, president; Mehmet Yalcinkaya, marketing assistant; and David Barach, [SST](#) publisher.

AD READERSHIP STUDY
Click here for results from our August 2003 Ad Readership Study

NEW FROM SOLID STATE TECHNOLOGY
SST Online and Nikkei Microdevices form Web alliance. Visit ne.nikkeibp.co.jp/NMD/ (Site is primarily in Japanese)

[2005 SST Resource Guide Questionnaire](#)

Best cost-of-ownership: Feinfocus' WBI-FOX inspection system. The WBI-FOX meets regulator automated handling standards for 200mm and 300mm wafer capability with a customized, automated wafer-handling system to prevent human interface with the wafers and flexible inspection processes (recipes) that adjust to specific wafer characteristics. Feinfocus, Stamford, CT; ph 978/794-5441, fax 978/688-8418, e-mail mgotha@wardhillmarketing.com, www.feinfocus.com.



Shown in this photo from left to right are: (standing) Kevin Fitzgerald, [SST](#) editor-in-chief; Kimbela Randle, regional manager; Chris Lastition, regional manager; Udo Frank, CTO; and David Barach, [SST](#) publisher; (kneeling) Jeff Stewart, system specialist; Micha Lehnigh, software engineer; and Jan Brinkkoetter, software engineer.

